

HIGH SPEED **1K X 8 DUAL-PORT** STATIC SRAM

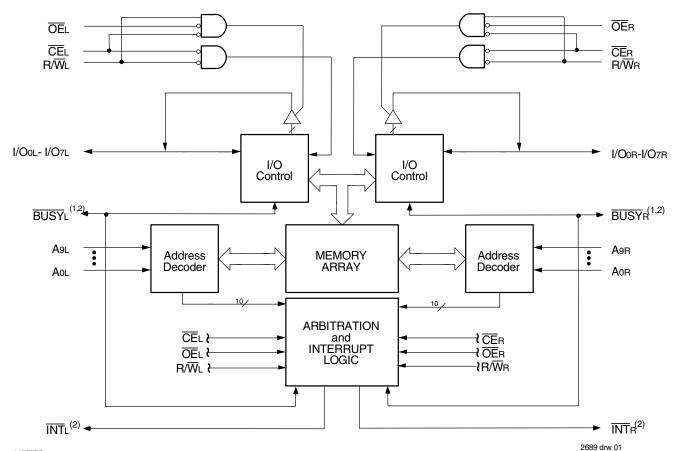
Features

- High-speed access
 - Commercial: 20/25/35/55/100ns (max.)

Functional Block Diagram

- Industrial: 25/55ns (max.)
- Military: 25/35/55/100ns (max.)
- Low-power operation
 - IDT7130/IDT7140SA
 - Active: 550mW (typ.)
 - Standby: 5mW (typ.)
 - IDT7130/IDT7140LA
 - Active: 550mW (typ.)
 - Standby: 1mW (typ.)
- ٠ MASTER IDT7130 easily expands data bus width to 16-ormore-bits using SLAVE IDT7140

- On-chip port arbitration logic (IDT7130 Only) • **BUSY** output flag on IDT7130; **BUSY** input on IDT7140
- INT flag for port-to-port communication
- Fully asynchronous operation from either port
- Battery backup operation-2V data retention (LA only) ٠
- TTL-compatible, single 5V ±10% power supply
- ٠ Military product compliant to MIL-PRF-38535 QML
- ٠ Industrial temperature range (-40°C to +85°C) is available for selected speeds
- ٠ Available in 48-pin DIP, LCC and Ceramic Flatpack, 52-pin PLCC, and 64-pin STQFP and TQFP
- ٠ Green parts available, see ordering information



NOTES:

1. IDT7130 (MASTER): $\overline{\text{BUSY}}$ is open drain output and requires pullup resistor.

IDT7140 (SLAVE): BUSY is input.

2. Open drain output: requires pullup resistor.



High-Speed 1K x 8 Dual-Port Static SRAM

Military, Industrial and Commercial Temperature Ranges

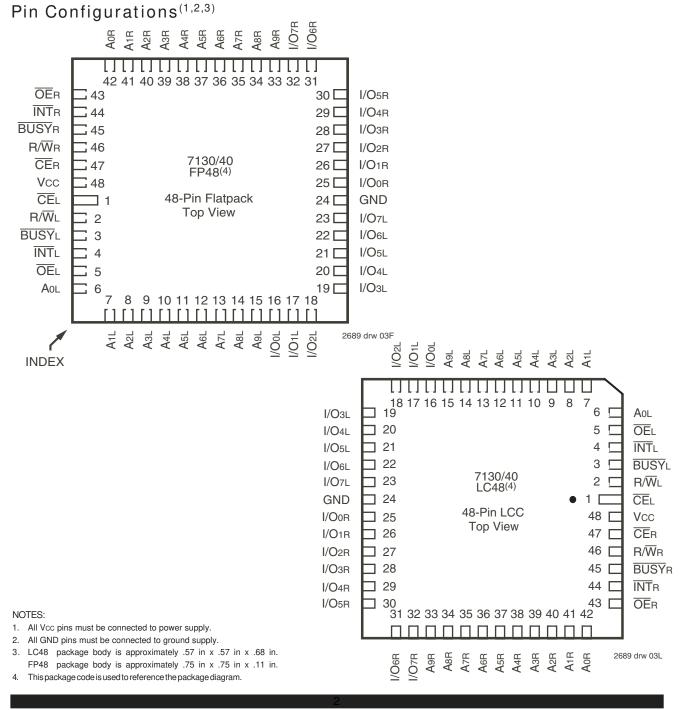
Description

The IDT7130/IDT7140 are high-speed 1K x 8 Dual-Port Static RAMs. The IDT7130 is designed to be used as a stand-alone 8-bit Dual-Port RAM or as a "MASTER" Dual-Port RAM together with the IDT7140 "SLAVE" Dual-Port in 16-bit-or-more word width systems. Using the IDT MASTER/SLAVE Dual-Port RAM approach in 16-ormore-bit memory system applications results in full-speed, errorfree operation without the need for additional discrete logic.

Both devices provide two independent ports with separate control, address, and I/O pins that permit independent asynchronous access for reads or writes to any location in memory. An automatic power down feature, controlled by \overline{CE} , permits the on chip circuitry of each port to enter a very low standby power mode.

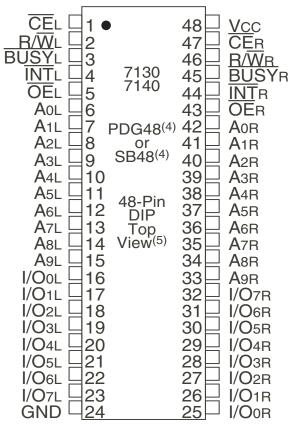
Fabricated using CMOS high-performance technology, these devices typically operate on only 550mW of power. Low-power (LA) versions offer battery backup data retention capability, with each Dual-Port typically consuming 200μ W from a 2V battery.

The IDT7130/IDT7140 devices are packaged in 48-pin sidebraze or plastic DIPs, LCCs, flatpacks, 52-pin PLCC, and 64-pin TQFP and STQFP. Military grade products are manufactured in compliance with the latest revision of MIL-PRF-38535 QML, making it ideally suited to military temperature applications demanding the highest level of performance and reliability.





Pin Configurations^(1,2,3) (con't.)



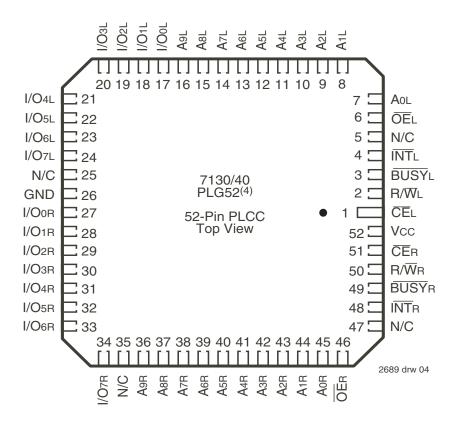
2689 drw 02

NOTES:

- 1. All Vcc pins must be connected to power supply.
- 2. All GND pins must be connected to ground supply.
- 3. PDG48 package body is approximately .55 in x .61 in x .19 in. SB48 package body is approximately .62 in x 2.43 in x .15 in.
- 4. This package code is used to reference the package diagram.
- 5. This text does not indicate orientation of the actual part-marking.



Pin Configurations^(1,2,3) (con't.)



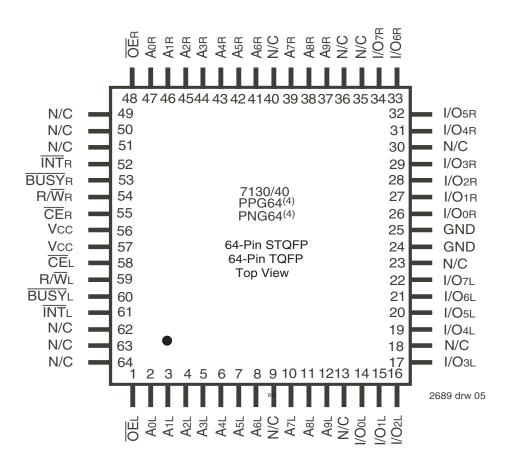
NOTES:

- 1. All Vcc pins must be connected to power supply.
- 2. All GND pins must be connected to ground supply.
- 3. PLG52 package body is approximately .75 in x .75 in x .17 in.
- 4. This package code is used to reference the package diagram.





Pin Configurations^(1,2,3) (con't.)



NOTES:

- 1. All Vcc pins must be connected to power supply.
- 2. All GND pins must be connected to ground supply.
- PPG64 package body is approximately 10 mm x 10 mm x 1.4mm.
 PNG64 package body is approximately 14mm x 14mm x 1.4mm.
- 4. This package code is used to reference the package diagram



High-Speed 1K x 8 Dual-Port Static SRAM

Military, Industrial and Commercial Temperature Ranges

Absolute Maximum Ratings⁽¹⁾

Symbol	Rating	Commercial & Industrial	Military	Unit
Vterm ⁽²⁾	Terminal Voltage with Respect to GND	-0.5 to +7.0	-0.5 to +7.0	V
TBIAS	Temperature Under Bias	-55 to +125	-65 to +135	°C
Тѕтс	Storage Temperature	-65 to +150	-65 to +150	°C
ЮИТ	DC Output Current	50	50	mA

NOTES:

2689 tbl 01

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of the specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- VTERM must not exceed Vcc + 10% for more than 25% of the cycle time or 10ns maximum, and is limited to ≤ 20mA for the period of VTERM ≥ Vcc + 10%.

Capacitance (TA = +25°C, f = 1.0MHz) STQFP and TQFP Packages Only

	Symbol	Parameter ⁽¹⁾	Conditions	Max.	Unit
	CiN	Input Capacitance	VIN = 3dV	9	pF
	Соит	Output Capacitance	Vout = 3dV	10	pF
Ì					2689 tbl 05

NOTES:

1. This parameter is determined by device characterization but is not production tested.

 3dV references the interpolated capacitance when the input and output signals switch from 0V to 3V or from 3V to 0V.

Recommended DC Operating Conditions

Symbol	Parameter	Min.	Тур.	Max.	Unit
Vcc	Supply Voltage	4.5	5.0	5.5	v
GND	Ground	0	0	0	V
Vн	Input High Voltage	2.2		6.0(2)	V
VIL	Input Low Voltage	-0.5 ⁽¹⁾		0.8	V

NOTES:

1. VIL (min.) \geq -1.5V for pulse width less than 10ns.

Recommended Operating

2. VTERM must not exceed Vcc + 10%.

Temperature and Supply Voltage ⁽¹⁾										
Grade Ambient GND Vcc Temperature										
Military	-55° C to $+125^{\circ}$ C	0V	5.0V <u>+</u> 10%							
Commercial	0° C to $+70^{\circ}$ C	0V	5.0V <u>+</u> 10%							

0V

NOTES:

Industrial

1. This is the parameter TA. This is the "instant on" case temperature.

-40°C to +85°C

DC Electrical Characteristics Over the Operating Temperature and Supply Voltage Range (Vcc = 5.0V ± 10%)

			7130SA 7140SA		7130LA 7140LA		
Symbol	Parameter	Test Conditions	Min.	Max.	Min.	Max.	Unit
L	Input Leakage Current ⁽¹⁾	Vcc = 5.5V, VIN = 0V to Vcc		10	-	5	μA
llo	Output Leakage Current ⁽¹⁾	$\frac{V_{CC}}{CE} = V_{IH}, V_{OUT} = 0V \text{ to } V_{CC}$		10		5	μA
Vol	Output Low Voltage (I/Oo-I/O7)	lol = 4mA	-	0.4	-	0.4	V
Vol	Open Drain O <u>utput</u> Low Voltage (<mark>BUSY</mark> , INT)	loL = 16mA		0.5	-	0.5	V
Vон	Output High Voltage	Юн = -4mA	2.4		2.4	_	V

NOTE:

1. At Vcc \leq 2.0V leakages are undefined.

2689 tbl 04

2689 tbl 02

5.0V + 10%

2689 tbl 03



2689 tbl 06a

DC Electrical Characteristics Over the Operating Temperature and Supply Voltage Range $^{(1,5)}$ (Vcc = 5.0V ± 10%)

								X20 ⁽²⁾ X20 ⁽²⁾ Only	7140 Com	0X25 0X25 I, Ind litary	7140 Co	0X35 0X35 m'l litary	
Symbol	Parameter	Test Condition	Versi	on	Тур.	Max.	Тур.	Max.	Тур.	Max.	Unit		
lcc	Dynamic Operating Current (Both Ports Active)	CEL and CER = VIL, Outputs Disabled f = fMAX ⁽³⁾	COM'L	SA LA	110 110	250 200	110 110	220 170	110 110	165 120	mA		
	(DUIT FOILS ACTIVE)	T = TMAX*'	MIL & IND	SA LA		_	110 110	280 220	110 110	230 170			
ISB1	Standby Current (Both Ports - TTL	\overline{CE}_{L} and $\overline{CE}_{R} = V_{IH}$ f = fMAX ⁽³⁾	COM'L	SA LA	30 30	65 45	30 30	65 45	25 25	65 45	mA		
	Level Inputs)		MIL & IND	SA LA	_		30 30	80 60	25 25	80 60			
ISB2	(One Port - TTL Active Port OutputsDisabled,		COM'L	SA LA	65 65	165 125	65 65	150 115	50 50	125 90	mA		
	Level Inputs)	f=fMAX ⁽³⁾	MIL & IND	SA LA			65 65	160 125	50 50	150 115			
ISB3	Full Standby Current (Both Ports -	$\overline{\underline{CE}}_{L} \text{ and } \overline{CE}_{R} \ge Vcc - 0.2V,$	COM'L	SA LA	1.0 0.2	15 5	1.0 0.2	15 5	1.0 0.2	30 10	mA		
	CMOS Level Inputs) $V_{IN} \ge V_{CC} - 0.2V \text{ or}$ $V_{IN} \le 0.2V, f = 0^{(4)}$		MIL & IND	SA LA			1.0 0.2	30 10					
ISB4	Full Standby Current (One Port -	$\overline{CE}^{*}A^{*} \leq 0.2V$ and $\overline{CE}^{*}B^{*} \geq VCC - 0.2V^{(6)}$	COM'L	SA LA	60 60	155 115	60 60	145 105	45 45	110 85	mA		
	CMOS Level Inputs)	$ \begin{array}{l} \forall \text{In} \geq Vcc - 0.2V \text{ or } \forall \text{In} \leq 0.2V \\ \text{Active Port Outputs Disabled,} \\ f = f_{\text{MAX}^{(3)}} \end{array} $	MIL & IND	SA LA			60 60	155 115	45 45	145 105			

			Test Condition Version		7130X55 7140X55 Com'l, Ind & Military		7130X100 7140X100 Com'l, Ind & Military		
Symbol	Parameter	Test Condition	Vers	ion	Тур.	Max.	Тур.	Max.	Unit
lcc	Dynamic Operating Current (Both Ports Active)	\overline{CEL} and $\overline{CER} = VIL$, Outputs Disabled	COM'L	SA LA	110 110	155 110	110 110	155 110	mA
	(Both Ports Active)	$f = fMAX^{(0)}$	MIL & IND	SA LA	110 110	190 140	110 110	190 140	
ISB1	Standby Current (Both Ports - TTL	$\overline{CE}_{L} \text{ and } \overline{CE}_{R} = V_{H}$ f = fmax $^{(6)}$	COM'L	SA LA	20 20	65 35	20 20	55 35	mA
	Level Inputs)		MIL & IND	SA LA	20 20	65 45	20 20	65 45	
ISB2	Standby Current (One Port - TTL	$\overline{CE}_{A^*} = V_{IL}$ and $\overline{CE}_{B^*} = V_{IH}^{(6)}$ Active Port Outputs Disabled,	COM'L	SA LA	40 40	110 75	40 40	110 75	mA
	Level Inputs)	f=fMAX ⁽³⁾	MIL & IND	SA LA	40 40	125 90	40 40	125 90	
ISB3	Full Standby Current (Both Ports - CMOS Level Inputs)	$\frac{\overline{CEL}}{\overline{CER}} \ge Vcc - 0.2V,$	COM'L	SA LA	1.0 0.2	15 4	1.0 0.2	15 4	mA
	CIVIOS Level Inputs)	$V_{\mathbb{N}} \ge V_{\mathbb{C}C} - 0.2V$ or $V_{\mathbb{N}} \le 0.2V$, $f = 0^{(4)}$	MIL & IND	SA LA	1.0 0.2	30 10	1.0 0.2	30 10	
ISB4	Full Standby Current (One Port -	$\overline{CE}^*A^* \leq 0.2V$ and $\overline{CE}^*B^* \geq VCC - 0.2V^{(6)}$	COM'L	SA LA	40 40	100 70	40 40	95 70	mA
	CMOS Level Inputs)	$V \mathbb{N} \ge V \mathbb{C} \mathbb{C} - 0.2V$ or $V \mathbb{N} \le 0.2V$ Active Port Outputs Disabled, $f = f_{MAX}^{(6)}$	MIL & IND	SA LA	40 40	110 85	40 40	110 80	
IOTES:		1	•			•		26	89 tbl 06t

NOTES:

1. 'X' in part numbers indicates power rating (SA or LA).

2. PLCC , TQFP and STQFP packages only.

3. At f = fMAX, address and control lines (except Output Enable) are cycling at the maximum frequency read cycle of 1/tcvc, and using "AC TEST CONDITIONS" of input levels of GND to 3V.

4. f = 0 means no address or control lines change. Applies only to inputs at CMOS level standby.

5. Vcc = 5V, TA=+25°C for Typ and is not production tested. Vcc DC = 100 mA (Typ)

6. Port "A" may be either left or right port. Port "B" is opposite from port "A".



/1305A/LA and /1405A/LA High-Speed 1K v 8 Dual-Port Static SBAM

Military, Industrial and Commercial Temperature Ranges

2689 tbl 07

Data Retention Characteristics (LA Version Only)

				71			
Symbol	Parameter	Test Condition	Min.	Typ. ⁽¹⁾	Max.	Unit	
VDR	Vcc for Data Retention			2.0	_		V
ICCDR	Data Retention Current		MIL. & IND.	_	100	4000	μA
		Vcc = 2.0V, $\overline{CE} \ge$ Vcc -0.2V	COM'L.	-	100	1500	
tcdr ⁽³⁾	Chip Deselect to Data Retention Time	V⊪ <u>></u> Vcc -0.2V or V⊪ <u><</u> 0.2V		0	-		ns
tR ⁽³⁾	Operation Recovery Time			tRC ⁽²⁾	_	_	ns

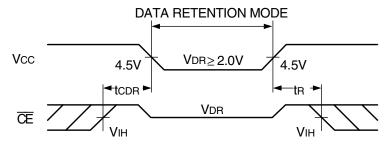
NOTES:

1. Vcc = 2V, $T_A = +25^{\circ}C$, and is not production tested.

2. tRc = Read Cycle Time

3. This parameter is guaranteed but not production tested.

Data Retention Waveform



2692 drw 06



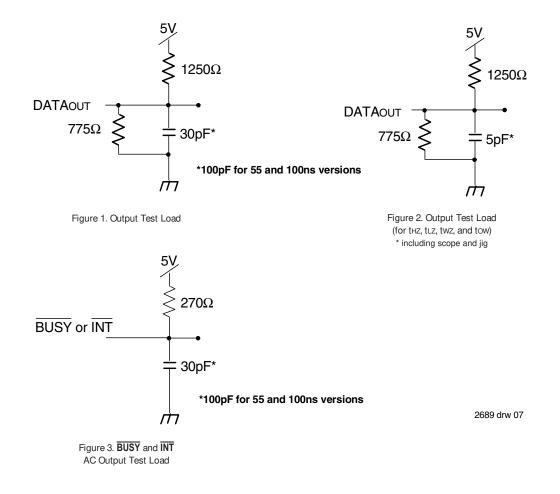


Military, Industrial and Commercial Temperature Ranges

AC Test Conditions

Input Pulse Levels	GND to 3.0V
Input Rise/Fall Times	5ns
Input Timing Reference Levels	1.5V
Output Reference Levels	1.5V
Output Load	Figures 1,2 and 3

2689 tbl 08



AC Electrical Characteristics Over the Operating Temperature Supply Voltage Range⁽³⁾

		7130X20 ⁽²⁾ 7130X25 7140X20 ⁽²⁾ 7140X25 Com'l Only Com'l, Ind & Military		7130X35 7140X35 Com'l & Military				
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Unit
READ CYCLE								
tRC	Read Cycle Time	20	-	25		35		ns
taa	Address Access Time		20		25		35	ns
tace	Chip Enable Access Time		20		25		35	ns
taoe	Output Enable Access Time		11		12		20	ns
tOH	Output Hold from Address Change	3		3		3		ns
t∟z	Output Low-Z Time ^(1,4)	0		0	-	0		ns
tHZ	Output High-Z Time ^(1,4)		10		10		15	ns
tPU	Chip Enable to Power Up Time ⁽⁴⁾	0	_	0		0		ns
tPD	Chip Disable to Power Down Time ⁽⁴⁾		20		25		35	ns

		714 Com	0X55 0X55 I, Ind litary	7130X100 7140X100 Com'l, Ind & Military		
Symbol	Parameter	Max.	Min.	Max.	Unit	
READ CYCLE						
tRC	Read Cycle Time	55		100		ns
taa	Address Access Time		55		100	ns
tACE	Chip Enable Access Time		55		100	ns
taoe	Output Enable Access Time		25		40	ns
tOH	Output Hold from Address Change	3		10		ns
tLZ	Output Low-Z Time ^(1,4)	5		5		ns
tHZ	Output High-Z Time ^(1,4)		25		40	ns
tPU	Chip Enable to Power Up Time ⁽⁴⁾	0	_	0		ns
tPD	Chip Disable to Power Down Time ⁽⁴⁾		50		50	ns

NOTES:

1. Transition is measured 0mV from Low or High-impedance voltage Output Test Load (Figure 2).

2. PLCC, TQFP and STQFP packages only.

3. 'X' in part numbers indicates power rating (SA or LA).

4. This parameter is guaranteed by device characterization, but is not production tested.

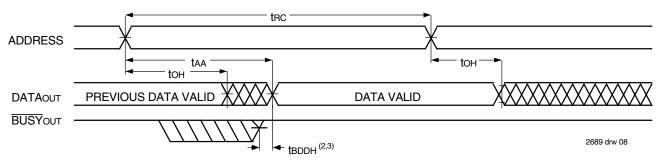




2689 tbl 09b

1		LA		1		/L	Α		
					-			OL	ODAL

Timing Waveform of Read Cycle No. 1, Either Side⁽¹⁾

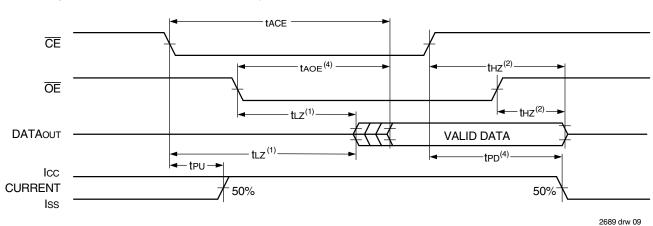


NOTES:

1. $R/\overline{W} = V_{IH}, \overline{CE} = V_{IL}$, and is $\overline{OE} = V_{IL}$. Address is valid prior to the coincidental with \overline{CE} transition LOW.

2. TEDD delay is required only in the case where the opposite port is completing a write operation to the same the address location. For simultaneous read operations, BUSY has no relationship to valid output data.

3. Start of valid data depends on which timing becomes effective last tAOE, tACE, tAA, and tBDD.



Timing Waveform of Read Cycle No. 2, Either Side⁽³⁾

NOTES:

- 1. Timing depends on which signal is asserted last, $\overline{\text{OE}}$ or $\overline{\text{CE}}$.
- 2. Timing depends on which signal is de-asserted first, $\overline{\text{OE}}$ or $\overline{\text{CE}}$.
- 3. $R/\overline{W} = V_{IH}$ and $\overline{OE} = V_{IL}$, and the address is valid prior to or coincidental with \overline{CE} transition LOW.

4. Start of valid data depends on which timing becomes effective last tAOE, tACE, tAA, and tBDD.





AC Electrical Characteristics Over the Operating Temperature Supply Voltage Range⁽⁵⁾

		714	0X20 ⁽²⁾ 0X20 ⁽²⁾ I Only	714 Com	7130X25 7140X25 Com'l, Ind & Military		7130X35 7140X35 Com'l & Military	
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Unit
WRITE CYCLE	E							
twc	Write Cycle Time ⁽³⁾	20		25		35		ns
tew	Chip Enable to End-of-Write	15		20		30		ns
taw	Address Valid to End-of-Write	15		20		30		ns
tas	Address Set-up Time	0		0		0		ns
twp	Write Pulse Width ⁽⁴⁾	15		15		25		ns
twR	Write Recovery Time	0		0		0		ns
tDW	Data Valid to End-of-Write	10		12		15		ns
tHZ	Output High-Z Time ⁽¹⁾	—	10		10		15	ns
tDH	Data Hold Time	0		0		0		ns
twz	Write Enable to Output in High-Z ⁽¹⁾		10		10		15	ns
tow	Output Active from End-of-Write ⁽¹⁾	0	_	0		0		ns
				_				2689 tbl 10
				714 Com	0X55 0X55 'I, Ind ilitary	7140 Com	0X100 0X100 'I, Ind ilitary	
Symbol	Parameter			Min.	Max.	Min.	Max.	Unit
WRITE CYCLI	E							
twc	Write Cycle Time ⁽³⁾			55		100		ns
tew	Chip Enable to End-of-Write			40		90		ns
taw	Address Valid to End-of-Write			40		90		ns
tas	Address Set-up Time			0		0		ns
twp	Write Pulse Width ⁽⁴⁾			30		55		ns
twR	Write Recovery Time			0		0		ns
tow	Data Valid to End-of-Write			20		40		ns
tHZ	Output High-Z Time ⁽¹⁾				25		40	ns

NOTES:

tDH

twz

tow

1. Transition is measured 0mV from Low or High-impedance voltage with Output Test Load (Figure 2). This parameter is guaranteed by device characterization but is not production tested.

0

0

25

0

0

ns

ns

2689 tbl 10b

40

2. PLCC, TQFP and STQFP packages only.

- 3. For MASTER/SLAVE combination, twc = tBAA + twP, since $R\overline{W}$ = VIL must occur after tBAA.
- 4. If OE is LOW during a R/W controlled write cycle, the write pulse width must be the larger of twp or (twz + tbw) to allow the I/O drivers to turn off data to be placed on the bus for the required tbw. If OE is HIGH during a R/W controlled write cycle, this requirement does not apply and the write pulse can be as short as the specified twp.

5. 'X' in part numbers indicates power rating (SA or LA).

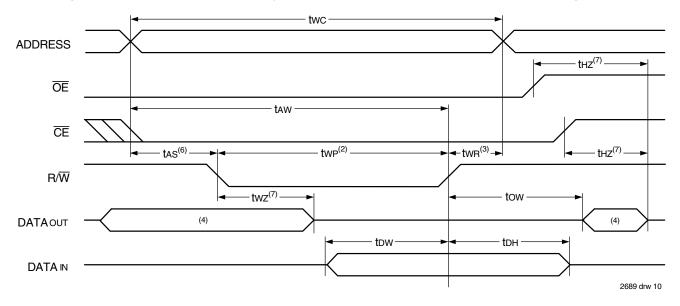
Data Hold Time

Write Enable to Output in High-Z⁽¹⁾

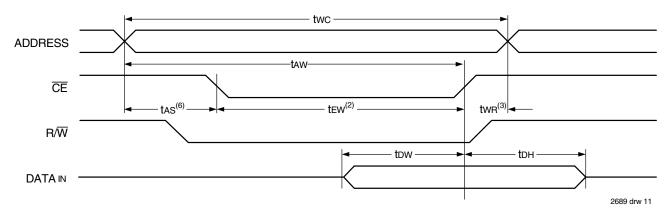
Output Active from End-of-Write⁽¹⁾



Timing Waveform of Write Cycle No. 1, (R/W Controlled Timing)^(1,5,8)



Timing Waveform of Write Cycle No. 2, (CE Controlled Timing)^(1,5)



NOTES:

1. R/ \overline{W} or \overline{CE} must be HIGH during all address transitions.

2. A write occurs during the overlap (tew or twp) of $\overline{CE} = VIL$ and $R/\overline{W} = VIL$.

3. two is measured from the earlier of \overline{CE} or R/W going HIGH to the end of the write cycle.

4. During this period, the I/O pins are in the output state and input signals must not be applied.

5. If the \overline{CE} LOW transition occurs simultaneously with or after the R/W LOW transition, the outputs remain in the HIGH impedance state.

6. Timing depends on which enable signal (\overline{CE} or R/\overline{W}) is asserted last.

7. This parameter is determined by device characterization, but is not production tested. Transition is measured 0mV from steady state with the Output Test Load (Figure 2).

8. If \overline{OE} is LOW during a R/W controlled write cycle, the write pulse width must be the larger of twp or (twz + tow) to allow the I/O drivers to turn off data to be placed on the bus for the required tow. If \overline{OE} is HIGH during a R/W controlled write cycle, this requirement does not apply and the write pulse can be as short as the specified twp.





AC Electrical Characteristics Over the Operating Temperature and Supply Voltage Range⁽⁷⁾

		714	0X20 ⁽¹⁾ 0X20 ⁽¹⁾ I Only	714 Com	0X25 0X25 'I, Ind litary	7140 Co	0X35 0X35 m'l litary	
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Unit
BUSY TIMING	G (For MASTER IDT 7130)	_		r				ī
tBAA	BUSY Access Time from Address		20		20		20	ns
tBDA	BUSY Disable Time from Address		20		20		20	ns
tBAC	BUSY Access Time from Chip Enable	—	20		20		20	ns
tBDC	BUSY Disable Time from Chip Enable	—	20		20		20	ns
twн	Write Hold After BUSY ⁽⁶⁾	12		15		20		ns
twdd	Write Pulse to Data Delay ⁽²⁾		40		50		60	ns
tDDD	Write Data Valid to Read Data Delay ⁽²⁾		30		35		35	ns
taps	Arbitration Priority Set-up Time ⁽³⁾	5		5		5		ns
tBDD	BUSY Disable to Valid Data ⁽⁴⁾		25		35	-	35	ns
BUSY INPUT	TIMING (For SLAVE IDT 7140)							
twв	Write to BUSY Input ⁽⁵⁾	0		0		0		ns
twн	Write Hold After BUSY ⁽⁶⁾	12	_	15		20	_	ns
twdd	Write Pulse to Data Delay ⁽²⁾	—	40		50		60	ns
tDDD	Write Data Valid to Read Data Delay ⁽²⁾	_	30		35		35	ns
						1		2689 tbl 11a
				7130X55 7140X55 Com'l, Ind & Military		7130X100 7140X100 Com'l, Ind & Military		
Symbol	Description			~		C	mary	
	Parameter			Min.	Max.	Min.	Max.	Unit
	G (For MASTER IDT 7130)				,		·	Unit
tBAA					,		·	Unit
tbaa tbda	G (For MASTER IDT 7130)			Min.	Max.		Max.	1
	G (For MASTER IDT 7130) BUSY Access Time from Address]			Min.	Max. 30		50	ns
tBDA	G (For MASTER IDT 7130) BUSY Access Time from Address] BUSY Disable Time from Address			Min.	Max. 30 30		Max.	ns ns
tBDA tBAC	G (For MASTER IDT 7130) BUSY Access Time from Address] BUSY Disable Time from Address BUSY Access Time from Chip Enable			Min.	Max. 30 30 30	Min.	Max. 50 50 50	ns ns ns
tBDA tBAC tBDC	G (For MASTER IDT 7130) BUSY Access Time from Address] BUSY Disable Time from Address BUSY Access Time from Chip Enable BUSY Disable Time from Chip Enable			Min.	Max. 30 30 30 30 30	Min.	Max. 50 50 50	ns ns ns ns
tBDA tBAC tBDC tWH	G (For MASTER IDT 7130) BUSY Access Time from Address] BUSY Disable Time from Address BUSY Access Time from Chip Enable BUSY Disable Time from Chip Enable Write Hold After BUSY ⁽⁶⁾			Min.	Max. 30 30 30 30 30 	Min.	Max. 50 50 50 50 50	ns ns ns ns
tBDA tBAC tBDC tWH tWDD	G (For MASTER IDT 7130) BUSY Access Time from Address] BUSY Disable Time from Address BUSY Access Time from Chip Enable BUSY Disable Time from Chip Enable Write Hold After BUSY ⁽⁶⁾ Write Pulse to Data Delay ⁽²⁾			Min.	Max. 30 30 30 30 30 30 80	Min.	Max. 50 50 50 50 120	ns ns ns ns ns ns
tBDA tBAC tBDC tWH tWD tDDD	G (For MASTER IDT 7130) BUSY Access Time from Address] BUSY Disable Time from Address BUSY Access Time from Chip Enable BUSY Disable Time from Chip Enable Write Hold After BUSY ⁶ Write Pulse to Data Delay ⁽²⁾ Write Data Valid to Read Data Delay ⁽²⁾			Min.	Max. 30 30 30 30 30 30 80	Min.	Max. 50 50 50 50 120	ns ns ns ns ns ns ns
teDA teAC teDC twH twDD tbDD taPS teDD	G (For MASTER IDT 7130) BUSY Access Time from Address] BUSY Disable Time from Address BUSY Access Time from Chip Enable BUSY Disable Time from Chip Enable Write Hold After BUSY ⁽⁶⁾ Write Pulse to Data Delay ⁽²⁾ Write Data Valid to Read Data Delay ⁽²⁾ Arbitration Priority Set-up Time ⁽³⁾			Min.	Max. 30 30 30 30 30 30 30 80 55 	Min.	Max. 50 50 50 50 50 120 100 	ns ns ns ns ns ns ns ns
teDA teAC teDC twH twDD twDD tbDD teDD teDD	G (For MASTER IDT 7130) BUSY Access Time from Address] BUSY Disable Time from Address BUSY Access Time from Chip Enable BUSY Disable Time from Chip Enable Write Hold After BUSY ⁽⁶⁾ Write Pulse to Data Delay ⁽²⁾ Write Data Valid to Read Data Delay ⁽²⁾ Arbitration Priority Set-up Time ⁽³⁾ BUSY Disable to Valid Data ⁽⁴⁾			Min.	Max. 30 30 30 30 30 30 30 80 55 	Min.	Max. 50 50 50 50 50 120 100 	ns ns ns ns ns ns ns ns
teda teac tebc twH twDD tbDD tebD BUSY INPUT	a (For MASTER IDT 7130) BUSY Access Time from Address] BUSY Disable Time from Address BUSY Access Time from Chip Enable BUSY Disable Time from Chip Enable Write Hold After BUSY ⁽⁶⁾ Write Pulse to Data Delay ⁽²⁾ Write Data Valid to Read Data Delay ⁽²⁾ Arbitration Priority Set-up Time ⁽³⁾ BUSY Disable to Valid Data ⁽⁴⁾ TIMING (For SLAVE IDT 7140)			Min.	Max. 30 30 30 30 30 30 30 30 55 55 55	Min.	Max. 50 50 50 50 50 120 120 100 65	ns ns ns ns ns ns ns ns ns
teda teac tebc twh twb twb tbbb tebb BUSY INPUT twb	G (For MASTER IDT 7130) BUSY Access Time from Address] BUSY Disable Time from Address BUSY Disable Time from Chip Enable BUSY Disable Time from Chip Enable Write Hold After BUSY ⁽⁶⁾ Write Pulse to Data Delay ⁽²⁾ Write Data Valid to Read Data Delay ⁽²⁾ Arbitration Priority Set-up Time ⁽³⁾ BUSY Disable to Valid Data ⁽⁴⁾ TIMING (For SLAVE IDT 7140) Write to BUSY Input ⁽⁶⁾			Min. 	Max. 30 30 30 30 30 30 30 55 55 	Min.	Max. 50 50 50 50 50 120 120 100 65	ns ns ns ns ns ns ns ns ns ns ns
EDA BAC BDC WH WDD DDD BDD BUDY INPUT WB	a (For MASTER IDT 7130) BUSY Access Time from Address] BUSY Disable Time from Address BUSY Access Time from Chip Enable BUSY Disable Time from Chip Enable Write Hold After BUSY ⁶ Write Pulse to Data Delay ⁽²⁾ Write Data Valid to Read Data Delay ⁽²⁾ Arbitration Priority Set-up Time ⁽³⁾ BUSY Disable to Valid Data ⁽⁴⁾ TIMING (For SLAVE IDT 7140) Write Hold After BUSY ⁽⁶⁾			Min. 	Max. 30 30 30 30 30 30 80 55 55 	Min.	Max. 50 50 50 50 120 100 65	ns ns ns ns ns ns ns ns ns ns ns ns

NOTES:

1. PLCC, TQFP and STQFP packages only.

2. Port-to-port delay through RAM cells from the writing port to the reading port, refer to "Timing Waveform of Write with Port -to-Port Read and BUSY."

3. To ensure that the earlier of the two ports wins.

4. tBDD is a calculated parameter and is the greater of 0, twDD - twP (actual) or tDDD - tDW (actual).

5. To ensure that a write cycle is inhibited on port 'B' during contention on port 'A'.

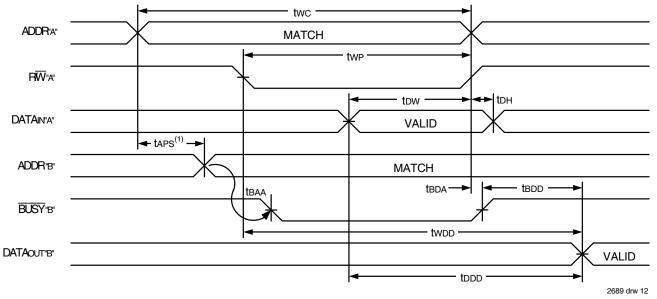
6. To ensure that a write cycle is completed on port 'B' after contention on port 'A'.

7. 'X' in part numbers indicates power rating (S or L).



2689 tbl 11b

Timing Waveform of Write with Port-to-Port Read and **BUSY**^(2,3,4)



NOTES:

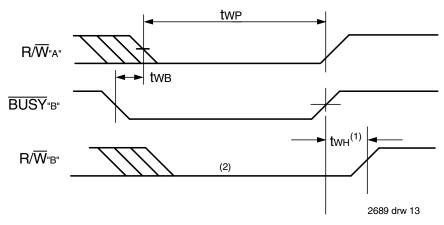
1. To ensure that the earlier of the two ports wins. tBDD is ignored for slave (IDT7140).

2. $\overline{CE}L = \overline{CE}R = VIL$

3. $\overline{OE} = V_{IL}$ for the reading port.

4. All timing is the same for the left and right ports. Port 'A' may be either the left or right port. Port "B" is opposite from port "A".

Timing Waveform of Write with **BUSY**⁽³⁾



NOTES:

1. twn must be met for both BUSY Input (IDT7140, slave) or Output (IDT7130 master).

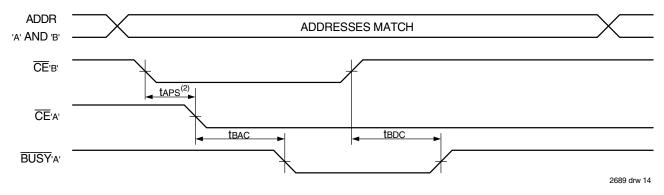
2. $\overline{\text{BUSY}}$ is asserted on port "B" blocking R/ $\overline{\text{W}}$ "B", until $\overline{\text{BUSY}}$ "B" goes HIGH.

3. All timing is the same for the left and right ports. Port "A" may be either the left or right port. Port "B" is opposite from port "A".

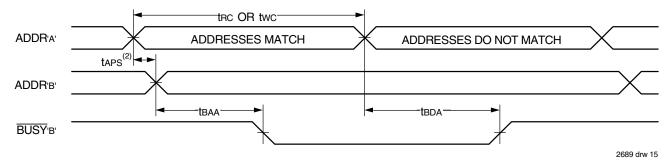




Timing Waveform of **BUSY** Arbitration Controlled by **CE** Timing⁽¹⁾



Timing Waveform by $\overline{\text{BUSY}}$ Arbitration Controlled by Address Match Timing^{(1)}



NOTES:

1. All timing is the same for left and right ports. Port "A" may be either left or right port. Port "B" is the opposite from port "A".

2. If tAPS is not satisfied, the BUSY will be asserted on one side or the other, but there is no guarantee on which side BUSY will be asserted (7130 only).

AC Electrical Characteristics Over the Operating Temperature and Supply Voltage Range⁽²⁾

		7140	X20 ⁽¹⁾ X20 ⁽¹⁾ Only	7140 Com')X25)X25 I, Ind litary	714 Co	0X35 0X35 om'l litary	
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Unit
INTERRUPT T	IMING							-
tas	Address Set-up Time	0	-	0		0		ns
twR	Write Recovery Time	0		0		0		ns
tiNS	Interrupt Set Time		20		25	-	25	ns
tinr	Interrupt Reset Time		20		25	-	25	ns

2689 tbl 12a

NOTES:

1. PLCC, TQFP and STQFP package only.

2. 'X' in part numbers indicates power rating (SA or LA).



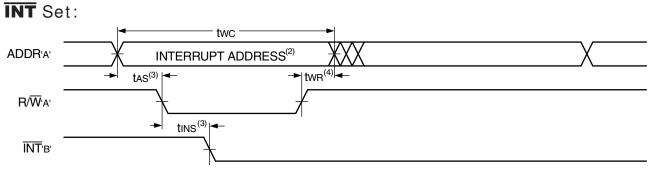
AC Electrical characteristics Over the Operating Temperature and Supply Voltage Range⁽¹⁾

		7140 Com	0X55 0X55 'I, Ind litary	7140 Com	X100 X100 I, Ind Iitary	
Symbol	Parameter	Min.	Max.	Min.	Max.	Unit
INTERRUPT T	IMING					
tas	Address Set-up Time	0		0	-	ns
twR	Write Recovery Time	0		0	-	ns
tins	Interrupt Set Time	_	45	_	60	ns
tinr	Interrupt Reset Time		45	-	60	ns

NOTES:

1. 'X' in part numbers indicates power rating (SA or LA).

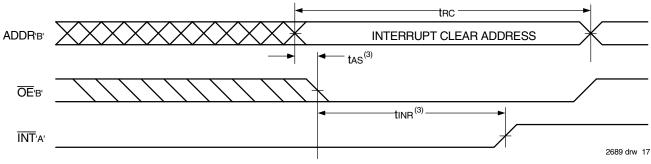
Timing Waveform of Interrupt Mode⁽¹⁾



2689 drw 16

2689 tbl 12b

INT Clear:



NOTES:.

1. All timing is the same for left and right ports. Port "A" may be either left or right port. Port "B" is the opposite from port "A".

2. See Interrupt Truth Table II.

3. Timing depends on which enable signal (\overline{CE} or $R/\overline{W})$ is asserted last.

4. Timing depends on which enable signal (\overline{CE} or R/\overline{W}) is de-asserted first.



Truth Tables

Truth Table I — Non-Contention Read/Write Control⁽⁴⁾

	Inputs ⁽¹⁾			
R∕ ₩	ĈĒ	ŌĒ	D0-7	Function
х	Н	х	Z	Port Disabled and in Power-Down Mode, IsB2 or IsB4
х	Н	Х	Z	$\overline{CE}_{R} = \overline{CE}_{L} = V_{IH}$, Power-Down Mode, ISB1 or ISB3
L	L	Х	DATAIN	Data on Port Written into Memory ⁽²⁾
Н	L	L	DATAOUT	Data in Memory Output on Port ⁶⁾
Н	L	Н	Z	High Impedance Outputs

NOTES:

1. $AOL - A1OL \neq AOR - A1OR$.

2. If $\overline{\text{BUSY}} = L$, data is not written.

3. If $\overline{\text{BUSY}}$ = L, data may not be valid, see twod and todd timing.

4. 'H' = VIH, 'L' = VIL, 'X' = DON'T CARE, 'Z' = HIGH IMPEDANCE

Truth Table II — Interrupt Flag^(1,4)

Left Port				Right Port						
R∕ W ∟	ĊĒ∟	ŌĒ∟	A9L-A0L	ĪNT∟	R∕ W R	CE R	OE R	A9R-A0R	INT R	Function
L	L	х	3FF	х	х	х	х	х	L ⁽²⁾	Set Right INTR Flag
х	х	х	х	х	х	L	L	3FF	H ⁽³⁾	Reset Right INTR Flag
х	х	х	х	L ⁽³⁾	L	L	х	3FE	х	Set Left INT∟ Flag
х	L	L	3FE	H ⁽²⁾	х	х	х	х	Х	Reset Left INT⊾ Flag

NOTES:

1. Assumes $\overline{\text{BUSY}}_{L} = \overline{\text{BUSY}}_{R} = V_{IH}$

2. If $\overline{BUSY}L = VIL$, then No Change.

3. If $\overline{\text{BUSY}}R = VIL$, then No Change.

4. 'H' = HIGH,' L' = LOW,' X' = DON'T CARE

Truth Table III — Address **BUSY** Arbitration

	Inputs			puts	
Ē	C E _R	Aol-A9l Aor-A9r	BUSTL ⁽¹⁾	BUSY R ⁽¹⁾	Function
х	х	NO MATCH	н	н	Normal
Н	х	MATCH	н	н	Normal
х	Н	MATCH	н	н	Normal
L	L	MATCH	(2)	(2)	Write Inhibit ⁽³⁾

NOTES:

2689 tbl 15

- 1. Pins \overline{BUSY}_L and \overline{BUSY}_R are both outputs for IDT7130 (master). Both are inputs for IDT7140 (slave). \overline{BUSY}_X outputs on the IDT7130 are open drain, not push-pull outputs. On slaves the \overline{BUSY}_X input internally inhibits writes.
- 2. 'L'if the inputs to the opposite port were stable prior to the address and enable inputs of this port. 'H' if the inputs to the opposite port became stable after the address and enable inputs of this port. If tAPS is not met, either \overline{BUSY}_{L} or $\overline{BUSY}_{R} = LOW$ will result. \overline{BUSY}_{L} and \overline{BUSY}_{R} outputs can not be LOW simultaneously.
- Writes to the left port are internally ignored when BUSYL outputs are driving LOW regardless of actual logic level on the pin. Writes to the right port are internally ignored when BUSYR outputs are driving LOW regardless of actual logic level on the pin.



2689 tbl 14

2689 tbl 13

Viab Speed 1K v 8 Dual Part Statia SPAN

Functional Description

The IDT7130/IDT7140 provides two ports with separate control, address and I/O pins that permit independent access for reads or writes to any location in memory. The IDT7130/IDT7140 has an automatic power down feature controlled by \overline{CE} . The \overline{CE} controls onchip power down circuitry that permits the respective port to go into a standby mode when not selected ($\overline{CE} = VIH$). When a port is enabled, access to the entire memory array is permitted.

Interrupts

If the user chooses the interrupt function, a memory location (mail box or message center) is assigned to each port. The left port interrupt flag (\overline{INT}_L) is asserted when the right port writes to memory location 3FE (HEX), where a write is defined as the $\overline{CE}_R = R/\overline{W}_R = V_{IL}$ per Truth Table II. The left port clears the interrupt by accessing address location 3FE when $\overline{CE}_L = \overline{OE}_L = V_{IL}, R/\overline{W}$ is a "don't care". Likewise, the right port interrupt flag (\overline{INT}_R) is asserted when the left port writes to memory location 3FF (HEX) and to clear the interrupt flag (\overline{INT}_R), the right port must access the memory location 3FF. The message (8 bits) at 3FE or 3FF is user-defined, since it is an addressable SRAM location. If the interrupt function is not used, address locations 3FE and 3FF are not used as mail boxes, but as part of the random access memory. Refer to Truth Table II for the interrupt operation.

Busy Logic

Busy Logic provides a hardware indication that both ports of the RAM have accessed the same location at the same time. It also allows one of the two accesses to proceed and signals the other side that the RAM is "Busy". The \overline{BUSY} pin can then be used to stall the access until the operation on the other side is completed. If a write operation has been attempted from the side that receives a \overline{BUSY} indication, the write signal is gated internally to prevent the write from proceeding.

The use of \overline{BUSY} logic is not required or desirable for all applications. In some cases it may be useful to logically OR the \overline{BUSY} outputs together and use any \overline{BUSY} indication as an interrupt source to flag the event of an illegal or illogical operation. In slave mode the \overline{BUSY} pin operates solely as a write inhibit input pin. Normal operation can be programmed by tying the \overline{BUSY} pins HIGH. If desired, unintended write operations can be prevented to a port by tying the \overline{BUSY} pin for that port LOW.

The $\overline{\text{BUSY}}$ outputs on the IDT7130 RAM (Master) are open drain type outputs and require open drain resistors to operate. If these

RAMs are being expanded in depth, then the BUSY indication for the resulting array does not require the use of an external AND gate.

Width Expansion with Busy Logic Master/Slave Arrays

When expanding an RAM array in width while using busy logic, one master part is used to decide which side of the RAM array will receive a busy indication, and to output that indication. Any number of slaves to be addressed in the same address range as the master, use the busy signal as a write inhibit signal. Thus on the IDT7130/IDT7140 RAMs the $\overline{\text{BUSY}}$ pin is an output if the part is Master (IDT7140) as shown in Figure 3.

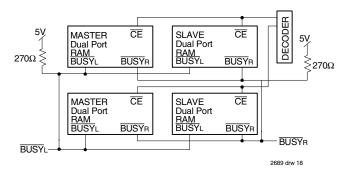


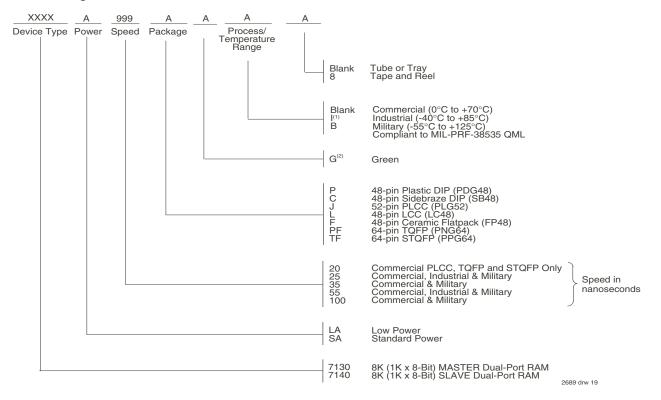
Figure 3. Busy and chip enable routing for both width and depth expansion with IDT7130 (Master) and IDT7140 (Slave)RAMs.

If two or more master parts were used when expanding in width, a split decision could result with one master indicating busy on one side of the array and another master indicating busy on one other side of the array. This would inhibit the write operations from one port for part of a word and inhibit the write operations from the other port for the other part of the word.

The \overline{BUSY} arbitration, on a Master, is based on the chip enable and address signals only. It ignores whether an access is a read or write. In a master/slave array, both address and chip enable must be valid long enough for a \overline{BUSY} flag to be output from the master before the actual write pulse can be initiated with either the R/\overline{W} signal or the byte enables. Failure to observe this timing can result in a glitched internal write inhibit signal and corrupted data in the slave.

High-Speed 1K x 8 Dual-Port Static SBAM

Ordering Information



NOTES:

1. Contact your local sales office for industrial temp range for other speeds, packages and powers.

 Green parts available. For specific speeds, packages and powers contact your local sales office.
 LEAD FINISH (SnPb) parts are Obsolete excluding FP48, LC48 & SB48. Product Discontinuation Notice - PDN# SP-17-02 Note that information regarding recently obsoleted parts are included in this datasheet for customer convenience.



/130SA/LA and /140SA/LA

Military, Industrial and Commercial Temperature Ranges

Orderable Part Information

Speed (ns)	Orderable Part ID	Pkg. Code	Pkg. Type	Temp. Grade
20	7130LA20JG	PLG52	PLCC	С
	7130LA20JG8	PLG52	PLCC	С
	7130LA20PFG	PNG64	TQFP	С
	7130LA20PFG8	PNG64	TQFP	С
	7130LA20TFG	PPG64	STQFP	С
	7130LA20TFG8	PPG64	STQFP	С
25	7130LA25JGI	PLG52	PLCC	I
	7130LA25JGI8	PLG52	PLCC	I
	7130LA25L48B	LC48	LCC	М
	7130LA25PFGI	PNG64	TQFP	I
	7130LA25PFGI8	PNG64	TQFP	I
	7130LA25TFGI	PPG64	STQFP	I
35	7130LA35C	SB48	SB	С
	7130LA35CB	SB48	SB	М
	7130LA35FB	FP48	FPACK	М
	7130LA35L48B	LC48	LCC	М
	7130LA35PDG	PDG48	PDIP	С
55	7130LA55C	SB48	SB	С
	7130LA55CB	SB48	SB	М
	7130LA55FB	FP48	FPACK	М
	7130LA55L48B	LC48	LCC	М
	7130LA55PDGI	PDG48	PDIP	I
100	7130LA100C	SB48	SB	С
	7130LA100CB	SB48	SB	М
	7130LA100L48B	LC48	LCC	М
	7130LA100PDG	PDG48	PDIP	С

Speed (ns)	Orderable Part ID	Pkg. Code	Pkg. Type	Temp. Grade
20	7140LA20JG	PLG52	PLCC	С
	7140LA20JG8	PLG52	PLCC	С
25	7140LA25PFG	PNG64	TQFP	С
	7140LA25PFG8	PNG64	TQFP	С
35	7140LA35CB	SB48	SB	М
	7140LA35FB	FP48	FPACK	М
	7140LA35L48B	LC48	LCC	М
	7140LA35PDG	PDG48	PDIP	С
55	7140LA55CB	SB48	SB	М
	7140LA55L48B	LC48	LCC	М
100	7140LA100CB	SB48	SB	М
	7140LA100L48B	LC48	LCC	М
	7140LA100PDG	PDG48	PDIP	С

Speed (ns)	Orderable Part ID	Pkg. Code	Pkg. Type	Temp. Grade
35	7140SA35CB	SB48	SB	М
	7140SA35L48B	LC48	LCC	М
55	7140SA55CB	SB48	SB	М
	7140SA55L48B	LC48	LCC	М
100	7140SA100CB	SB48	SB	М

Speed (ns)	Orderable Part ID	Pkg. Code	Pkg. Type	Temp. Grade
25	7130SA25L48B	LC48	LCC	М
35	7130SA35C	SB48	SB	С
	7130SA35CB	SB48	SB	М
	7130SA35L48B	LC48	LCC	М
55	7130SA55C	SB48	SB	С
	7130SA55CB	SB48	SB	М
	7130SA55L48B	LC48	LCC	М
100	7130SA100C	SB48	SB	С
	7130SA100CB	SB48	SB	М
	7130SA100L48B	LC48	LCC	М



Datasheet Document History

03/15/99:

		Converted to new format
		Cosmetic and typographical corrections
	Pages 2 and 3	Added additional notes to pin configurations
06/08/99:		Changed drawing format
08/02/99:	Page 2	Corrected package number in note 3
09/29/99:	Page 2	Fixed pin 1 in DIP pin configuration
11/10/99:	Page 1 & 18	Replaced IDT logo
06/23/00:	Page 4	Increased storage temperature parameters
		Clarified TA parameter
	Page 5	DC Electrical parameters-changed wording from "open" to "disabled"
	Page 10	Changed ±500mV to 0mV in notes
01/08/02:	Page 1	Added Ceramic Flatpack to 48-pin package offerings
	Page 2 & 3	Added date revision to pin configurations
	Page 4, 5, 8, 10,	Removed industrial temp option footnote from all tables
	12,14 & 15	
01/08/02:	Page 5, 8, 10, 12, & 14	Added industrial temp for 25ns to DC & AC Electrical Characteristics
01/00/01	Page 5, 8, 10, 12, & 14	Removed industrial temp for 35ns to DC & AC Electrical Characteristics
	Page 18	Added industrial temp for 25ns and removed industrial temp for 35ns in ordering information
	. ago . o	Updated industrial temp option footnote
	Page 1 & 19	Replaced IDT ™ logo with IDT ® logo
01/11/06:	Page 1	Added green availability to features
017117001	Page 18	Added green indicator to ordering information
	Page 1 & 19	Replaced old IDT TM with new IDT TM logo
04/14/06:	Page 18	Added "PDG" footnote to the ordering information
10/21/08:	Page 18	Removed "IDT" from orderable part number
01/21/13:	Page 2	Added L48-1 package and F48-1 package pin configurations
0.12.1.101		with corresponding foot notes
	Page 13, 18, 19 & 20	Typo/corrections
	Page 20	Added T & Reel indicator to ordering information
05/20/16:	Page 2	Split the F48 and L48 pin configuration, creating two separate pin configurations:
00/20/10:	r ugo E	F48 pin ceramic flatpack rotated 90 degrees counterclockwise, removed footnote 5 reference
		and L48 LCC rotated 90 degrees clockwise to reflect pin 1 orientation and added dot at pin 1,
		removed footnote 5 reference
	Page 3	P48 plastic DIP and C48 sidebrazed DIP, removed half moon and to reflect pin 1 orientation
		added dot at pin 1
	Page 4	J52 PLCC rotated 90 degrees clockwise to reflect pin 1 orientation added dot at pin 1, removed
		footnote 5 reference
	Page 5	PN64 TQFP and PP64 STQFP, chamfer removed, rotated 90 degrees counterclockwise to
		reflect pin 1 orientation and added dot at pin 1, removed footnote 5 reference
	Page 20	All incidences of -1 , -2 have been removed from the datasheet
02/13/18:	1 490 20	Product Discontinuation Notice - PDN# SP-17-02
		Last time buy expires June 15, 2018
07/12/21:	Page 1 - 23	Rebranded as Renesas datasheet
<i>UTTE/ET.</i>	Page 1 & 21	Deleted obsolete Industrial speed grade for 100ns
	Page 2, 3, 4 & 5	Updated package codes
	Page 21	Added Orderable Part Information tables

Initiated datasheet document history



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